

High Temperature Silicon Carbide Power Schottky Diode

V_{RRM}	=	650 V
V_F	=	1.3 V
I_F	=	2.5 A
Q_C	=	20 nC

Features

- 650 V Schottky rectifier
- 250 °C maximum operating temperature
- Electrically isolated base-plate
- Zero reverse recovery charge
- Superior surge current capability
- Positive temperature coefficient of V_F
- Temperature independent switching behavior
- Lowest figure of merit Q_C/I_F
- Available screened to Mil-PRF-19500

Advantages

- High temperature operation
- Improved circuit efficiency (Lower overall cost)
- Low switching losses
- Ease of paralleling devices without thermal runaway
- Smaller heat sink requirements
- Industry's lowest reverse recovery charge
- Industry's lowest device capacitance
- Ideal for output switching of power supplies
- Best in class reverse leakage current at operating temperature

Maximum Ratings at T_j = 250 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit
Repetitive peak reverse voltage	V _{RRM}		650	V
Continuous forward current	I _F	T _C ≤ 225 °C	2.5	A
RMS forward current	I _{F(RMS)}	T _C ≤ 225 °C	4.3	A
Surge non-repetitive forward current, Half Sine Wave	I _{F,SM}	T _C = 25 °C, t _p = 10 ms	32	A
Non-repetitive peak forward current	I _{F,max}	T _C = 25 °C, t _p = 10 μs	120	A
i ² t value	∫i ² dt	T _C = 25 °C, t _p = 10 ms	5	A ² S
Power dissipation	P _{tot}	T _C = 25 °C	66	W
Operating and storage temperature	T _j , T _{stg}		-55 to 250	°C

Electrical Characteristics at T_j = 250 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Diode forward voltage	V _F	I _F = 2.5 A, T _j = 25 °C	1.3			V
		I _F = 2.5 A, T _j = 250 °C	2.0			
Reverse current	I _R	V _R = 650 V, T _j = 25 °C	1	5		μA
		V _R = 650 V, T _j = 250 °C	10	100		
Total capacitive charge	Q _C	I _F ≤ I _{F,MAX}	20			nC
Switching time	t _s	dI _F /dt = 200 A/μs	V _R = 400 V	< 25		ns
		T _j = 210 °C	V _R = 400 V			
Total capacitance	C	V _R = 1 V, f = 1 MHz, T _j = 25 °C	274			pF
		V _R = 400 V, f = 1 MHz, T _j = 25 °C	31			
		V _R = 650 V, f = 1 MHz, T _j = 25 °C	29			

Thermal Characteristics

Thermal resistance, junction - case	R _{thJC}	3.4	°C/W
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Mechanical Properties

Mounting torque	M	0.6	Nm
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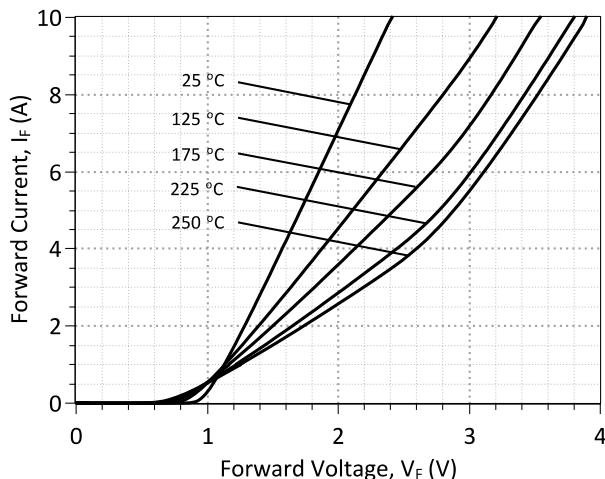


Figure 1: Typical Forward Characteristics

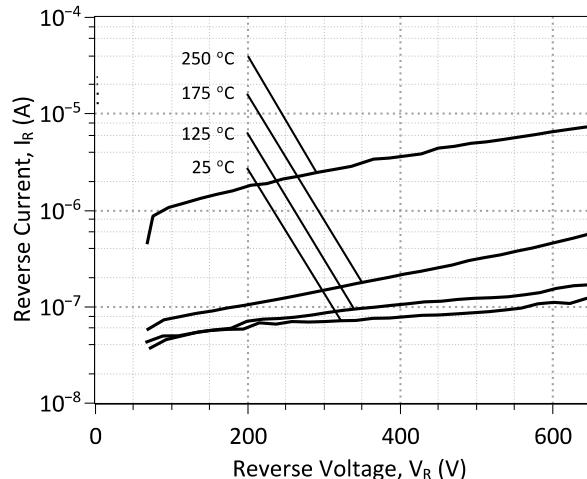


Figure 2: Typical Reverse Characteristics

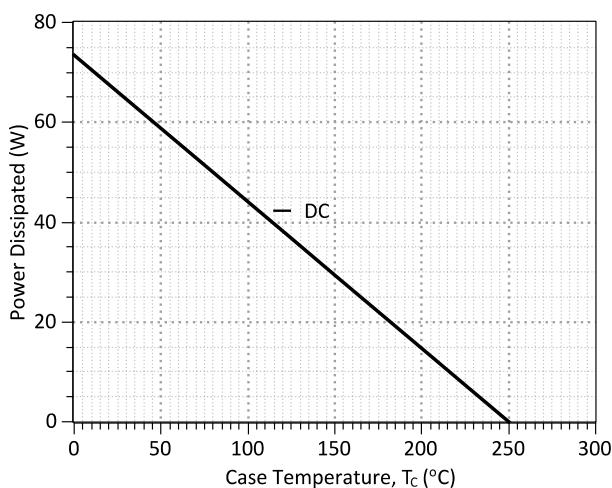


Figure 3: Power Derating Curve

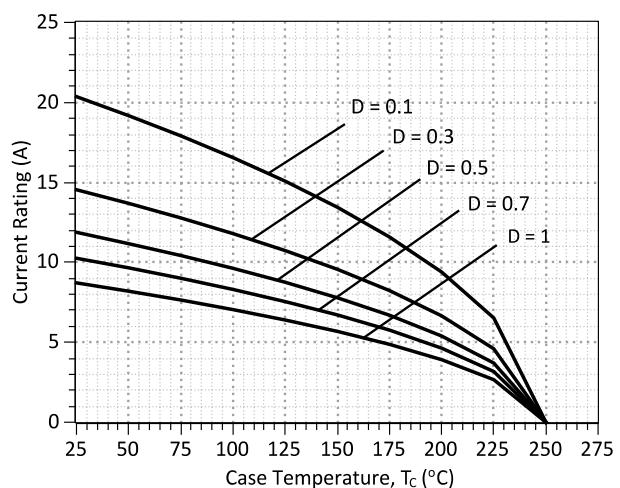


Figure 4: Current Derating Curves ($D = t_p/T$, $t_p = 400 \mu s$)
 (Considering worst case Z_{th} conditions)

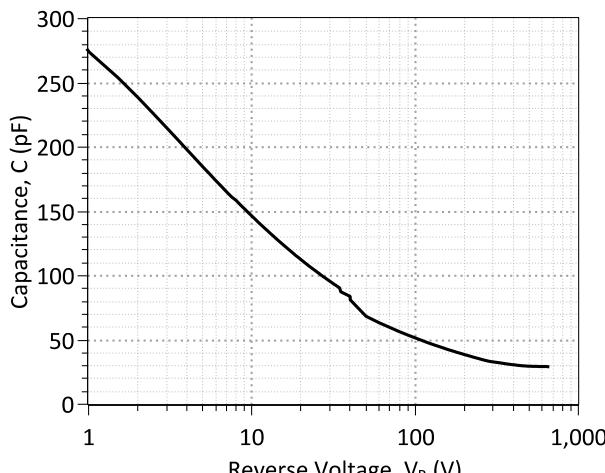


Figure 5: Typical Junction Capacitance vs Reverse Voltage Characteristics

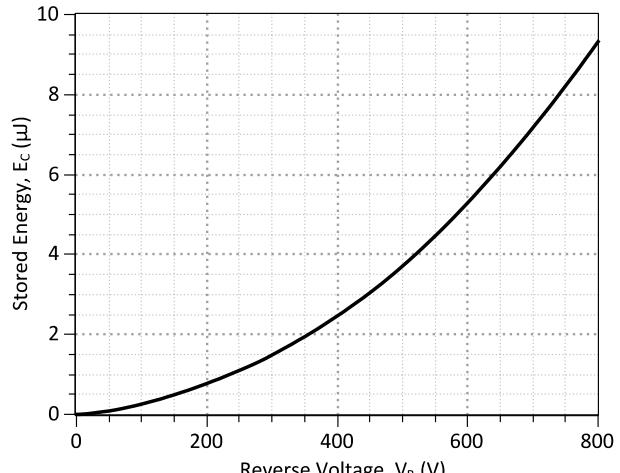


Figure 6: Typical Switching Energy vs Reverse Voltage Characteristics

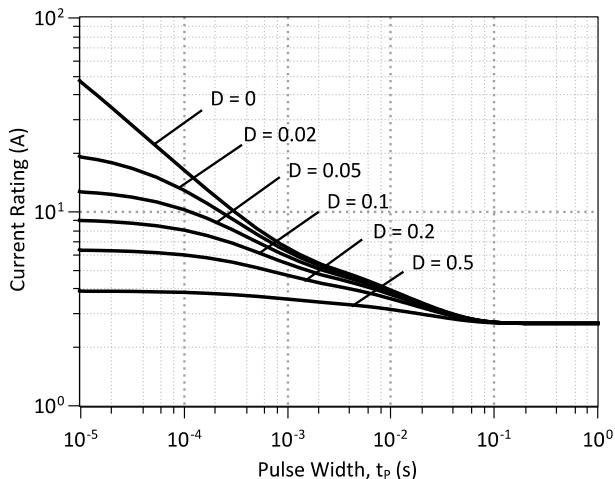


Figure 7: Current vs Pulse Duration Curves at $T_c = 225\text{ }^\circ\text{C}$

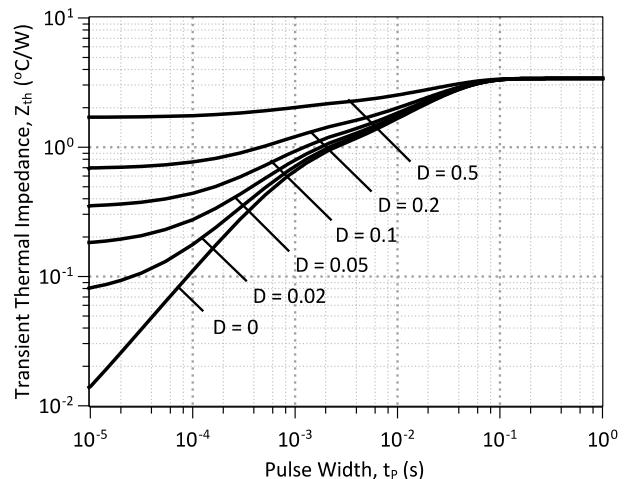
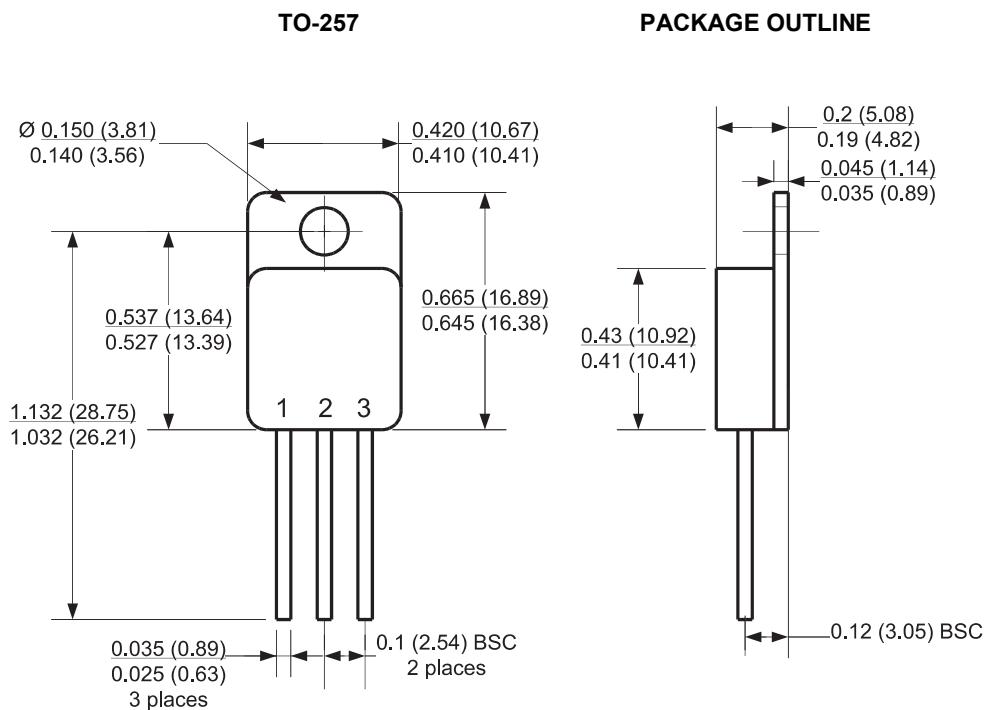


Figure 8: Transient Thermal Impedance

Package Dimensions:



NOTE

1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS



1N8032-GA

Revision History			
Date	Revision	Comments	Supersedes
2013/11/13	1	Updated Electrical Characteristics	
2012/04/24	0	Initial release	

Published by

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SPICE Model Parameters

Copy the following code into a SPICE software program for simulation of the 1N8032-GA device.

```
* MODEL OF GeneSiC Semiconductor Inc.  
*  
* $Revision: 1.0      $  
* $Date: 05-SEP-2013 $  
*  
* GeneSiC Semiconductor Inc.  
* 43670 Trade Center Place Ste. 155  
* Dulles, VA 20166  
* http://www.genesicsemi.com/index.php/hit-sic/schottky  
*  
* COPYRIGHT (C) 2013 GeneSiC Semiconductor Inc.  
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*  
* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY  
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED  
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A  
* PARTICULAR PURPOSE."  
* Models accurate up to 2 times rated drain current.  
*  
* Start of 1N8032-GA SPICE Model  
*.SUBCKT 1N8032 ANODE KATHODE  
D1 ANODE KATHODE 1N8032_25C; Call the Schottky Diode Model  
D2 ANODE KATHODE 1N8032_PIN; Call the PiN Diode Model  
.MODEL 1N8032_25C D  
+ IS      1.99E-17      RS      0.12463  
+ N       1              IKF     569.082  
+ EG      1.2            XTI     3  
+ TRS1    0.0035        TRS2    3.87E-05  
+ CJO     3.38E-10      VJ      0.41772  
+ M       1.5479         FC      0.5  
+ TT      1.00E-10       BV      650  
+ IBV    1.00E-03       VPK     650  
+ IAVE    5              TYPE    Sic_Schottky  
+ MFG     GeneSiC_Semiconductor  
.MODEL 1N8032_PIN D  
+ IS      1.33E-10      RS      0.31147  
+ N       5              IKF     0  
+ EG      3.23           XTI     -10  
+ FC      0.5            TT      0  
+ BV      650            IBV    1.00E-03  
+ VPK    650            IAVE    5  
+ TYPE   Sic_Pin  
.ENDS  
*  
* End of 1N8032-GA SPICE Model
```